

MILITARY SPECIFICATION

TRANSISTOR, PNP, SILICON
TYPE 2N2378

This Amendment forms a part of Military Specification MIL-S-19500/289(EL), 24 April 1964.

Page 2, paragraph 3.5: Replace with the following:

"3.5 Marking. - Except as otherwise specified herein, marking shall be in accordance with Specification MIL-S-19500. If any specification-requirements waiver has been granted, the product-identification marking shall consist of the 'classification' type designation only. The 'manufacturer's identification' and 'country of origin' may, at option of the manufacturer, be omitted from being marked on the semiconductor device covered herein.

Page 2, paragraph 3.5.1: Delete.

Page 3, paragraph 4.3.2: Change paragraph to read:

"4.3.2 Qualification end-point test measurements. - All applicable end-point test measurements shall be made within four (4) hours after the particular sample units have been subjected to the required physical-mechanical or environmental test. This 'interval' requirement shall not be applicable to measurements specified to be made during (subjection of sample units to) a physical-mechanical or environmental test, and shall not be applicable where otherwise specified for life test(s)."

Page 3, Table I, Subgroup 3, Breakdown Voltage, Collector-To-Emitter test: In Conditions column, replace " $I_E = 0$ " with " $I_B = 0$ ".

Page 4, Table I, Subgroup 4, Hole Storage test: In Conditions column, replace "f=10 mc" with the following:

"f=25 pulses/sec
of square wave:"

Custodian:
ARMY-EL

Preparing activity:
ARMY-EL

Project No. 5961-A029

FSC 5961